

WEDNESDAY 31.8.			
		09:30	Get Together & Registration
Tutorial		10:00	FIB preparation of lamellae on chips for in-situ TEM and other techniques <i>J. Reuteler</i>
		12:00	LUNCH
Session n°1	Talk 1	13:00	Tungsten based SQUID Nanofabrication by means of Focused Ion Beam Induced Deposition - <i>F. Sigloch</i>
	Talk 2	13:25	Comparing Contrast in nano-CT and FIB/SEM Tomography of an Al Cast Alloy – A Correlative Microscopy Study - <i>C. Pauly</i>
	Exi 1	13:50	Explore unlimited process pathways for FIB nanopatterning and ion imaging using VELION - <i>T. Richter (Raith)</i>
	Talk 3	14:15	3D Nanoprinting of Electrical AFM Nanoprobes - <i>L. M. Seewald</i>
		14:45	COFFEE BREAK
Session n°2	Inv 1	15:30	Manipulation and Study of Antiferromagnetic Order Enabled by Focused Ion Beam Fabrication - <i>S. Haley</i>
	Talk 4	16:05	Backside FIB/SEM analysis strategy to identify a new failure mode at an automotive magnetic sensor device - <i>M. Simon-Najasek</i>
	Exi 2	16:30	in situ Force Measurements - the FIB/SEM as a Mechanical Characterization Tool - <i>A.J. Smith (Kleindiek)</i>
	Talk 5	16:55	Development and SEM integration of the Nano Aperture Ion Source - <i>M.L. Simons</i>
	Exi 3	17:20	The latest automation application software for lamellae fabrication and 3D volume reconstruction - <i>M. Wu (Thermo-Fisher)</i>
		17:45	Food Truck + beers + posters